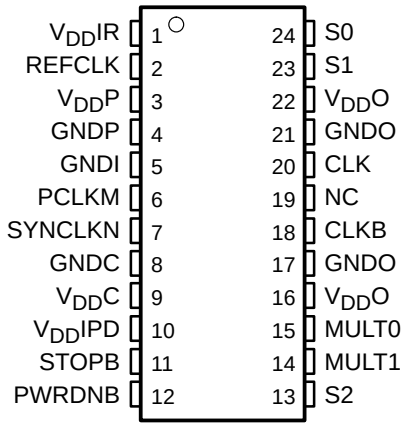
- **533-MHz Differential Clock Source for Direct Rambus™ Memory Systems for an 1066-MHz Data Transfer Rate**
- **Synchronizes the Clock Domains of the Rambus Channel With an External System or Processor Clock**
- **Three Power Operating Modes to Minimize Power for Mobile and Other Power-Sensitive Applications**
- **Operates From a Single 3.3-V Supply and 120 mW at 300 MHz (Typ)**
- **Packaged in a Shrink Small-Outline Package (DBQ)**
- **Supports Frequency Multipliers: 4, 6, 8, 16/3**
- **No External Components Required for PLL**
- **Supports Independent Channel Clocking**
- **Spread Spectrum Clocking Tracking Capability to Reduce EMI**
- **Designed for Use With TI's 133-MHz Clock Synthesizers CDC924 and CDC921**
- **Cycle-Cycle Jitter Is Less Than 40 ps at 533 MHz**
- **Certified by Gigatest Labs to Exceed the Rambus DRCG Validation Requirement**
- **Supports Industrial Temperature Range of –40°C to 85°C**

DBQ PACKAGE
(TOP VIEW)



NC – No internal connection

description

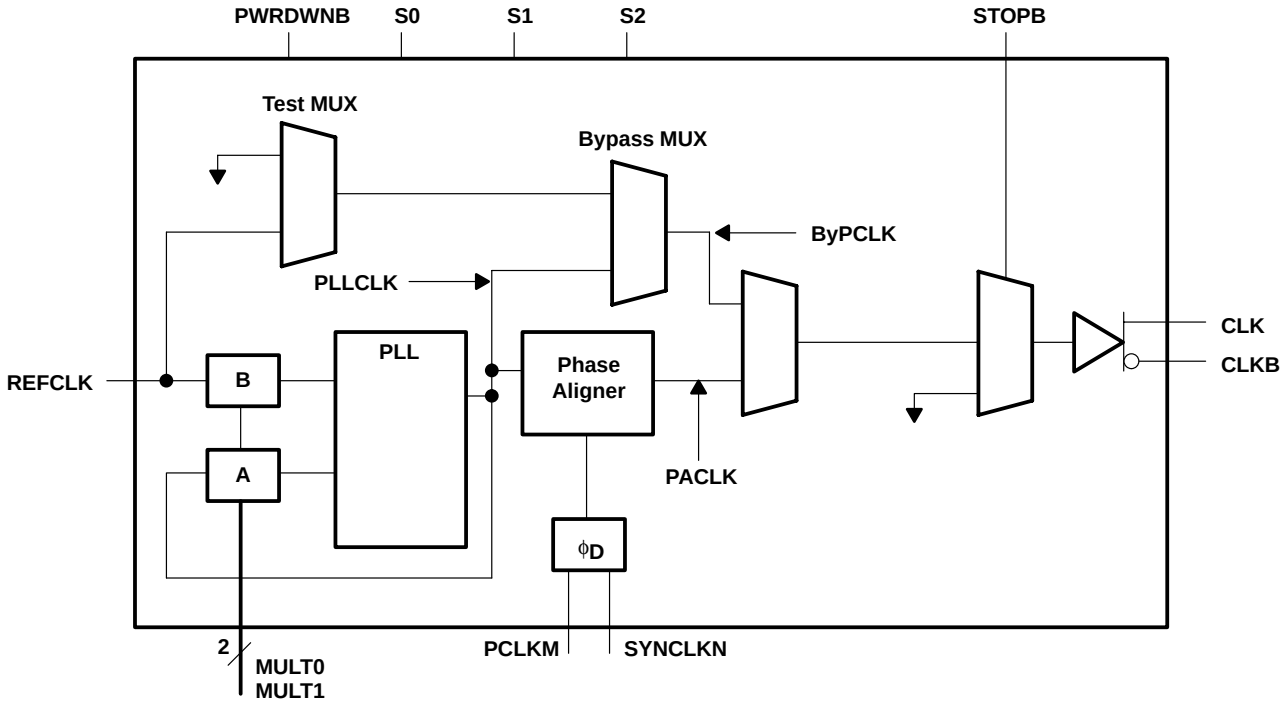
The Direct Rambus clock generator (DRCG) provides the necessary clock signals to support a Direct Rambus memory subsystem. It includes signals to synchronize the Direct Rambus channel clock to an external system or processor clock. It is designed to support Direct Rambus memory on a desktop, workstation, server, and mobile PC motherboards. DRCG also provides an off-the-shelf solution for a broad range of Direct Rambus memory applications.

The DRCG provides clock multiplication and phase alignment for a Direct Rambus memory subsystem to enable synchronous communication between the Rambus channel and ASIC clock domains. In a Direct Rambus memory subsystem, a system clock source provides the REFCLK and PCLK clock references to the DRCG and memory controller, respectively. The DRCG multiplies REFCLK and drives a high-speed BUSCLK to RDRAMs and the memory controller. Gear ratio logic in the memory controller divides the PCLK and BUSCLK frequencies by ratios M and N such that PCLKM = SYNCLKN, where SYNCLK = BUSCLK/4. The DRCG detects the phase difference between PCLKM and SYNCLKN and adjusts the phase of BUSCLK such that the skew between PCLKM and SYNCLKN is minimized. This allows data to be transferred across the SYNCLK/PCLK boundary without incurring additional latency.

User control is provided by multiply and mode selection terminals. The multiply terminals provide selection of one of four clock frequency multiply ratios, generating BUSCLK frequencies ranging from 267 MHz to 533 MHz with clock references ranging from 33 MHz to 100 MHz. The mode select terminals can be used to select a bypass mode where the frequency multiplied reference clock is directly output to the Rambus channel for systems where synchronization between the Rambus clock and a system clock is not required. Test modes are provided to bypass the PLL and output REFCLK on the Rambus channel and to place the outputs in a high-impedance state for board testing.

The CDCFR83 is characterized for operation over free-air temperatures of –40°C to 85°C.

functional block diagram



FUNCTION TABLE†

MODE	S0	S1	S2	CLK	CLKB
Normal	0	0	0	Phase aligned clock	Phase aligned clock B
Bypass	1	0	0	PLLCLK	PLLCLKB
Test	1	1	0	REFCLK	REFCLKB
Output test (OE)	0	1	X	Hi-Z	Hi-Z
Reserved	0	0	1	—	—
Reserved	1	0	1	—	—
Reserved	1	1	1	Hi-Z	Hi-Z

† X = don't care, Hi-Z = high impedance

Terminal Functions

TERMINAL NAME	TERMINAL NO.	I/O	DESCRIPTION
CLK	20	O	Output clock
CLKB	18	O	Output clock (complement)
GNDC	8		GND for phase aligner
GNDI	5		GND for control inputs
GNDO	17, 21		GND for clock outputs
GNDP	4		GND for PLL
MULT0	15	I	PLL multiplier select
MULT1	14	I	PLL multiplier select
NC	19		Not used
PCLKM	6	I	Phase detector input
PWRDNB	12	I	Active low power down
REFCLK	2	I	Reference clock
S0	24	I	Mode control
S1	23	I	Mode control
S2	13	I	Mode control
STOPB	11	I	Active low output disable
SYNCLKN	7	I	Phase detector input
$V_{DD}C$	9		V_{DD} for phase aligner
$V_{DD}IPD$	10		Reference voltage for phase detector inputs and STOPB
$V_{DD}IR$	1		Reference voltage for REFCLK
$V_{DD}O$	16, 22		V_{DD} for clock outputs
$V_{DD}P$	3		V_{DD} for PLL

PLL divider selection

Table 1 lists the supported REFCLK and BUSCLK frequencies. Other REFCLK frequencies are permitted, provided that (267 MHz < BUSCLK < 533 MHz) and (33 MHz < REFCLK < 100 MHz).

Table 1. REFCLK and BUSCLK Frequencies

MULT0	MULT1	REFCLK (MHz)	MULTIPLY RATIO	BUSCLK (MHz)
0	0	67	4	267
0	1	50	6	300
0	1	67	6	400
1	1	33	8	267
1	1	50	8	400
1	1	67	8	533
1	0	67	16/3	356

Table 2. Clock Output Driver States

STATE	PWRDNB	STOPB	CLK	CLKB
Powerdown	0	X	GND	GND
CLK stop	1	0	$V_{X, STOP}$	$V_{X, STOP}$
Normal	1	1	PACLK/PLLCLK/ REFCLK†	PACLKB/PLLCLKB/ REFCLKB

† Depending on the state of S0, S1, and S2

absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V_{DD} (see Note 1) . . . . . –0.5 V to 4 V
Output voltage range, V_O, at any output terminal . . . . . –0.5 V to V_{DD} + 0.5 V
Input voltage range,V_I, at any input terminal . . . . . –0.5 V to V_{DD} + 0.5 V
Continuous total power dissipation . . . . . see Dissipation Rating Table
Operating free-air temperature range, T_A . . . . . –40°C to 85°C
Storage temperature range, T_{stg} . . . . . –65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds . . . . . 260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to the GND terminals.

DISSIPATION RATING TABLE

PACKAGE	$T_A \le 25°C$ POWER RATING	DERATING FACTOR ABOVE $T_A = 25°C$‡	$T_A = 70°C$ POWER RATING	$T_A = 85°C$ POWER RATING
DBQ	1400 mW	11 mW/°C	905 mW	740 mW

‡ This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V_{DD}	3.135	3.3	3.465	V
High-level input voltage, V_{IH} (CMOS)	$0.7 \times V_{DD}$			V
Low-level input voltage, V_{IL} (CMOS)			$0.3 \times V_{DD}$	V
Initial phase error at phase detector inputs (required range for phase aligner)	$-0.5 \times t_{c(PD)}$		$0.5 \times t_{c(PD)}$	
REFCLK low-level input voltage, V_{IL}			$0.3 \times V_{DD}$IR	V
REFCLK high-level input voltage, V_{IH}	$0.7 \times V_{DD}$IR			V
Input signal low voltage, V_{IL} (STOPB)			$0.3 \times V_{DD}$IPD	V
Input signal high voltage, V_{IH} (STOPB)	$0.7 \times V_{DD}$IPD			V
Input reference voltage for (REFCLK) (V_{DD}IR)	1.235		3.465	V
Input reference voltage for (PCLKM and SYSCLKN) (V_{DD}IPD)	1.235		3.465	V
High-level output current, I_{OH}			–16	mA
Low-level output current, I_{OL}			16	mA
Operating free-air temperature, T_A	–40		85	°C

timing requirements

	MIN	MAX	UNIT
Input cycle time, $t_{c(in)}$	10	40	ns
Input cycle-to-cycle jitter		250	ps
Input duty cycle over 10,000 cycles	40%	60%	
Input frequency modulation, f_{mod}	30	33	kHz
Modulation index, nonlinear maximum 0.5%		0.6%	
Phase detector input cycle time (PCLKM and SYNCLKN)	30	100	ns
Input slew rate, SR	1	4	V/ns
Input duty cycle (PCLKM and SYNCLKN)	25%	75%	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS†		MIN	TYP‡	MAX	UNIT
$V_{O(STOP)}$	Output voltage during CLK Stop (STOPB = 0)		See Figure 1		1.1		2	
$V_{O(X)}$	Output crossing-point voltage		See Figure 1 and Figure 6		1.3		1.8	V
V_O	Output voltage swing		See Figure 1		0.4		0.6	V
V_{IK}	Input clamp voltage		V_{DD} = 3.135 V,	I_I = –18 mA			–1.2	V
V_{OH}	High-level output voltage		See Figure 1				2	V
			V_{DD} = min to max,	I_{OH} = –1 mA	V_{DD} – 0.1 V			
			V_{DD} = 3.135 V,	I_{OH} = –16 mA	2.4			
V_{OL}	Low-level output voltage		See Figure 1		1			V
			V_{DD} = min to max,	I_{OL} = 1 mA			0.1	
			V_{DD} = 3.135 V,	I_{OL} = 16 mA			0.5	
I_{OH}	High-level output current		V_{DD} = 3.135 V,	V_O = 1 V	–32	–52		mA
			V_{DD} = 3.3 V,	V_O = 1.65 V		–51		
			V_{DD} = 3.465 V,	V_O = 3.135 V		–14.5	–21	
I_{OL}	Low-level output current		V_{DD} = 3.135 V,	V_O = 1.95 V	43	61.5		mA
			V_{DD} = 3.3 V,	V_O = 1.65 V		65		
			V_{DD} = 3.465 V,	V_O = 0.4 V		25.5	36	
I_{OZ}	High-impedance-state output current		S0 = 0, S1 = 1				±10	µA
$I_{OZ(STOP)}$	High-impedance-state output current during CLK stop		Stop = 0, V_O = GND or V_{DD}				±100	µA
$I_{OZ(PD)}$	High-impedance-state output current in power-down state		PWRDNB = 0, V_O = GND or V_{DD}		–10		100	µA
I_{IH}	High-level input current	REFCLK, PCLKM, SYNCLKN, STOPB	V_{DD} = 3.465 V,	V_I = V_{DD}			10	µA
		PWRDNB, S0, S1, S2, MULT0, MULT1	V_{DD} = 3.465 V,	V_I = V_{DD}			10	
I_{IL}	Low-level input current	REFCLK, PCLKM, SYNCLKN, STOPB	V_{DD} = 3.465 V,	V_I = 0			–10	µA
		PWRDNB, S0, S1, S2, MULT0, MULT1	V_{DD} = 3.465 V,	V_I = 0			–10	
Z_O	Output impedance	High state	R_I at I_O –14.5 mA to –16.5 mA		15	35	50	Ω
		Low state	R_I at I_O 14.5 mA to 16.5 mA		11	17	35	
	Reference current	$V_{DD}IR$, $V_{DD}IPD$	V_{DD} = 3.465 V	PWRDNB = 0			50	µA
				PWRDNB = 1			0.5	mA
C_I	Input capacitance		V_I = V_{DD} or GND			2		pF
C_O	Output capacitance		V_O = V_{DD} or GND			3		pF
$I_{DD(PD)}$	Supply current in power-down state		REFCLK = 0 MHz to 100 MHz, PWDNB = 0, STOPB = 1				100	µA
$I_{DD(CLKSTOP)}$	Supply current in CLK stop state		BUSCLK configured for 533 MHz				45	mA
$I_{DD(NORMAL)}$	Supply current in normal state		BUSCLK = 533 MHz				100	mA

† V_{DD} refers to any of the following; V_{DD}, $V_{DD}IPD$, $V_{DD}IR$, $V_{DD}O$, $V_{DD}C$, and $V_{DD}P$
‡ All typical values are at V_{DD} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER				TEST CONDITIONS	MIN	TYP†	MAX	UNIT
$t_{c(out)}$	Clock output cycle time				1.87		3.75	ns
$t_{(jitter)}$	Total cycle jitter over 1, 2, 3, 4, 5, or 6 clock cycles	Infinite and stopped phase alignment	267 MHz	See Figure 3			80	ps
			300 MHz				70	
			356 MHz				60	
			400 MHz				50	
			533 MHz§				40	
$t_{(phase)}$	Phase detector phase error for distributed loop			Static phase error‡	–100		100	ps
$t_{(phase, SSC)}$	PLL output phase error when tracking SSC			Dynamic phase error‡	–100		100	ps
$t_{(DC)}$	Output duty cycle over 10,000 cycles			See Figure 4	45%		55%	
$t_{(DC, err)}$	Output cycle-to-cycle duty cycle error	Infinite and stopped phase alignment	267 MHz	See Figure 5			80	ps
			300 MHz				70	
			356 MHz				60	
			400 MHz				50	
			533 MHz				50	
t_r, t_f	Output rise and fall times (measured at 20%–80% of output voltage)			See Figure 7	160		400	ps
Δt	Difference between rise and fall times on a single device (20%–80%) $\lvert t_f - t_r \rvert$			See Figure 7			100	ps

† All typical values are at V_{DD} = 3.3 V, T_A = 25°C.
‡ Assured by design
§ Jitter measurement according to Rambus validation specification

state transition latency specifications

PARAMETER		FROM	TO	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
$t_{(powerup)}$	Delay time, PWRDNB↑ to CLK/CLKB output settled (excluding $t_{(DISTLOCK)}$)	Powerdown	Normal	See Figure 8			3	ms
	Delay time, PWRDNB↑ to internal PLL and clock are on and settled						3	
$t_{(VDDpowerup)}$	Delay time, power up to CLK/CLKB output settled	V_{DD}	Normal	See Figure 8			3	ms
	Delay time, power up to internal PLL and clock are on and settled						3	
$t_{(MULT)}$	MULT0 and MULT1 change to CLK/CLKB output resettled (excluding $t_{(DISTLOCK)}$)	Normal	Normal	See Figure 9			1	ms
$t_{(CLKON)}$	STOPB↑ to CLK/CLKB glitch-free clock edges	CLK Stop	Normal	See Figure 10			10	ns
$t_{(CLKSETL)}$	STOPB↑ to CLK/CLKB output settled to within 50 ps of the phase before STOPB was disabled	CLK Stop	Normal	See Figure 10			20	cycles
$t_{(CLKOFF)}$	STOPB↓ to CLK/CLKB output disabled	Normal	CLK Stop	See Figure 10			5	ns

† All typical values are at V_{DD} = 3.3 V, T_A = 25°C.

state transition latency specifications (continued)

PARAMETER		FROM	TO	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
$t_{(powerdown)}$	Delay time, PWRDNB↓ to the device in the power-down mode	Normal	Powerdown	See Figure 8			1	ms
$t_{(STOP)}$	Maximum time in CLKSTOP (STOPB = 0) before reentering normal mode (STOPB = 1)	STOPB	Normal	See Figure 10			100	µs
$t_{(ON)}$	Minimum time in normal mode (STOPB = 1) before reentering CLKSTOP (STOPB = 0)	Normal	CLK stop	See Figure 10	100			ms
$t_{(DISTLOCK)}$	Time from when CLK/CLKB output is settled to when the phase error between SYNCLKN and PCLKM falls within $t_{(phase)}$	Unlocked	Locked				5	ms

† All typical values are at V_{DD} = 3.3 V, T_A = 25°C.

PARAMETER MEASUREMENT INFORMATION

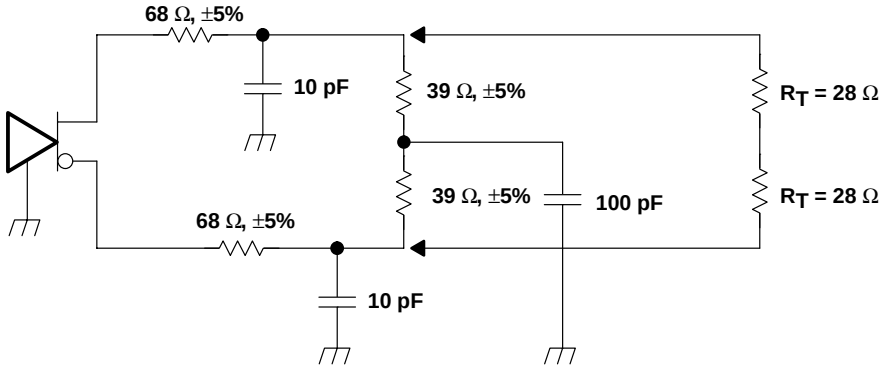
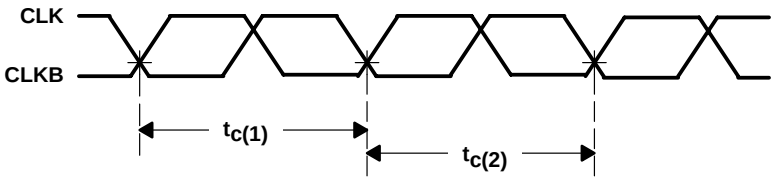


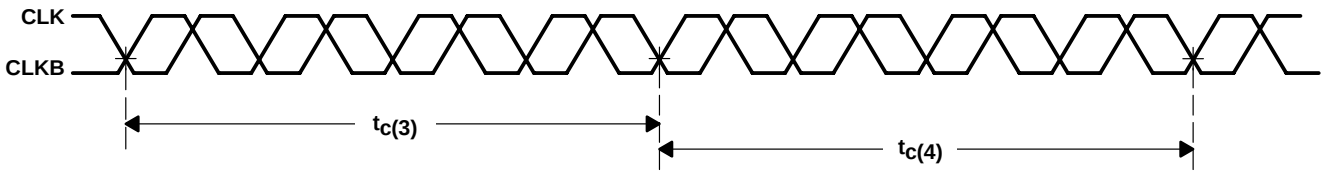
Figure 1. Test Load and Voltage Definitions ($V_{O(STOP)}$, $V_{O(X)}$, V_O, V_{OH}, V_{OL})



Cycle-to-cycle jitter = | $t_{c(1)}$ − $t_{c(2)}$| over 10000 consecutive cycles

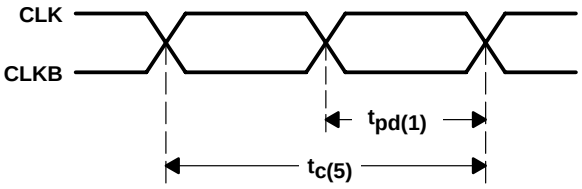
Figure 2. Cycle-to-Cycle Jitter

PARAMETER MEASUREMENT INFORMATION



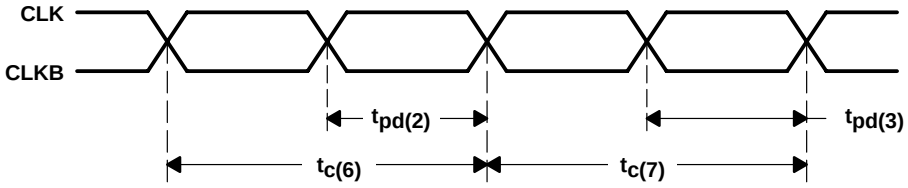
Cycle-to-cycle jitter = $| t_{c(3)} - t_{c(4)} |$ over 10000 consecutive cycles

Figure 3. Short Term Cycle-to-Cycle Jitter Over Four Cycles



Duty cycle = $(t_{pd(1)}/t_{c(5)})$

Figure 4. Output Duty Cycle



Duty cycle error = $t_{pd(2)} - t_{pd(3)}$

Figure 5. Duty Cycle Error (Cycle-to-Cycle)

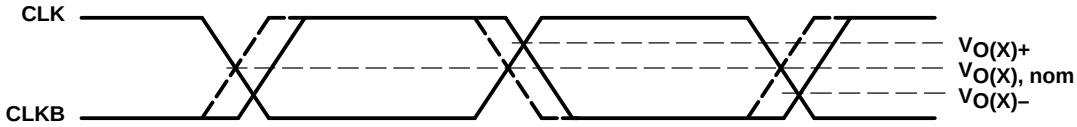


Figure 6. Crossing-Point Voltage

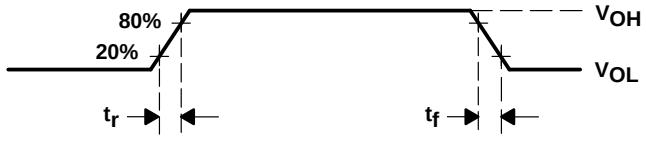


Figure 7. Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION

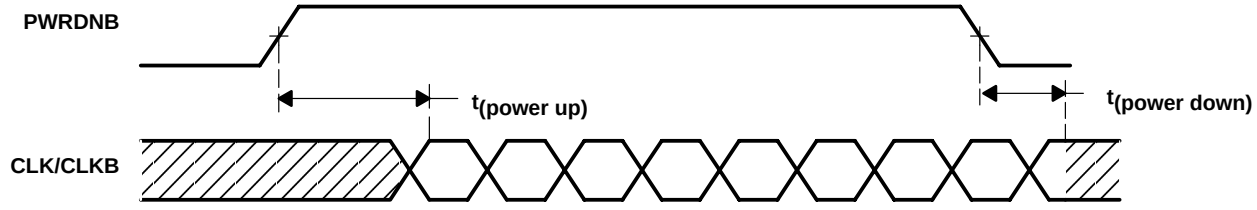


Figure 8. PWRDNB Transition Timings

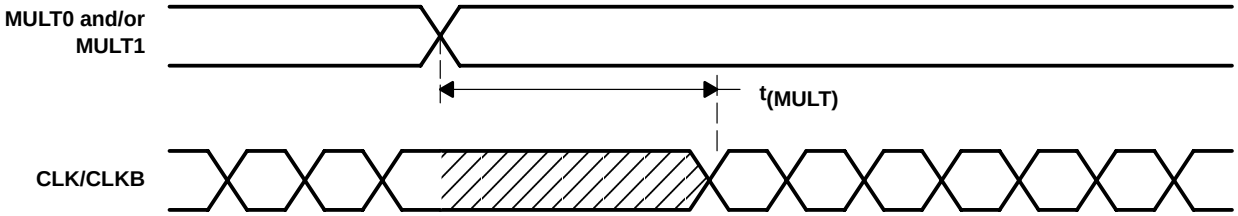
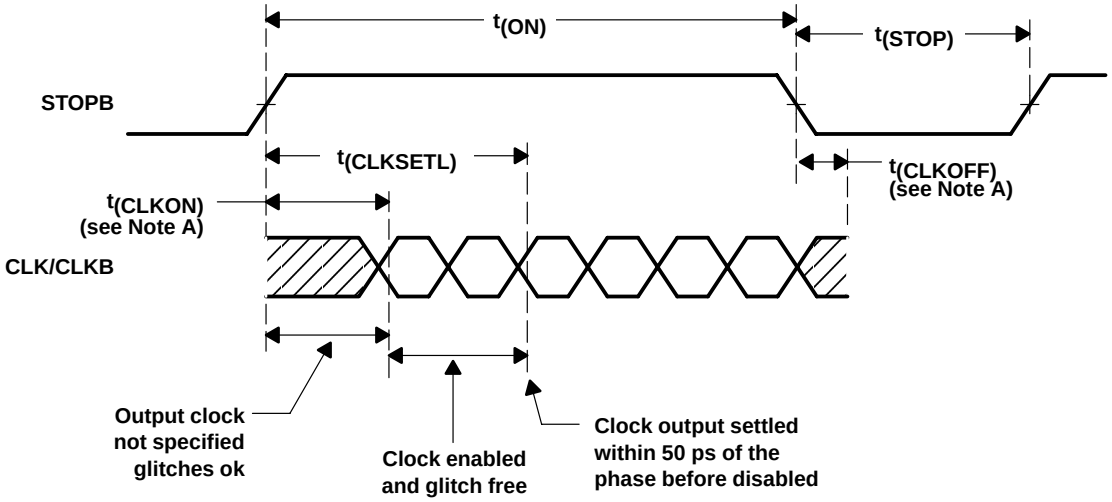


Figure 9. MULT Transition Timings



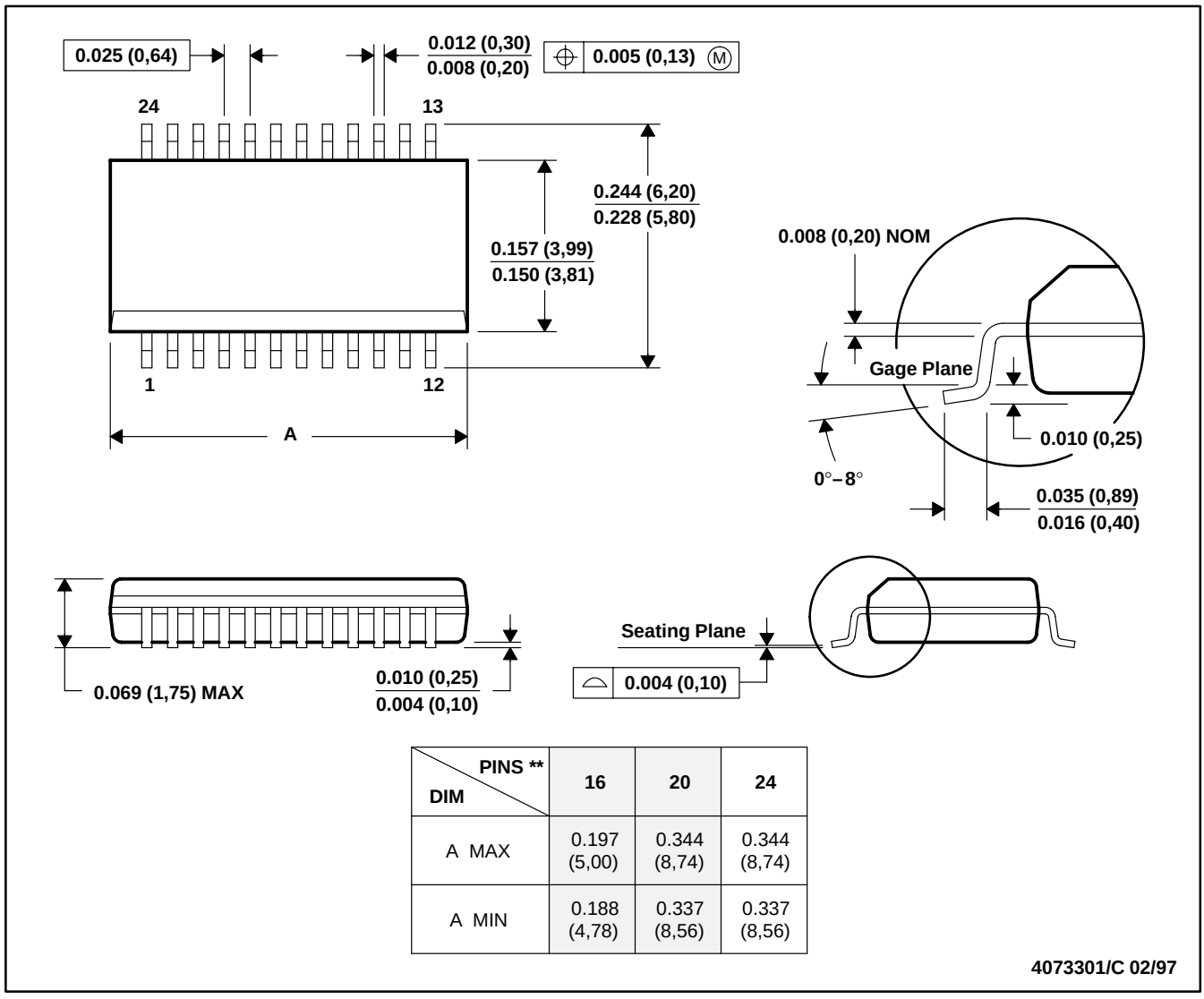
NOTE A: $V_{ref} = V_O \pm 200$ mV

Figure 10. STOPB Transition Timings

MECHANICAL DATA

DBQ (R-PDSO-G)** **PLASTIC SMALL-OUTLINE PACKAGE**

24-PIN SHOWN



DIM \ PINS **	16	20	24
A MAX	0.197 (5,00)	0.344 (8,74)	0.344 (8,74)
A MIN	0.188 (4,78)	0.337 (8,56)	0.337 (8,56)

4073301/C 02/97

NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
D. Falls within JEDEC MO-137

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